FIG. 1

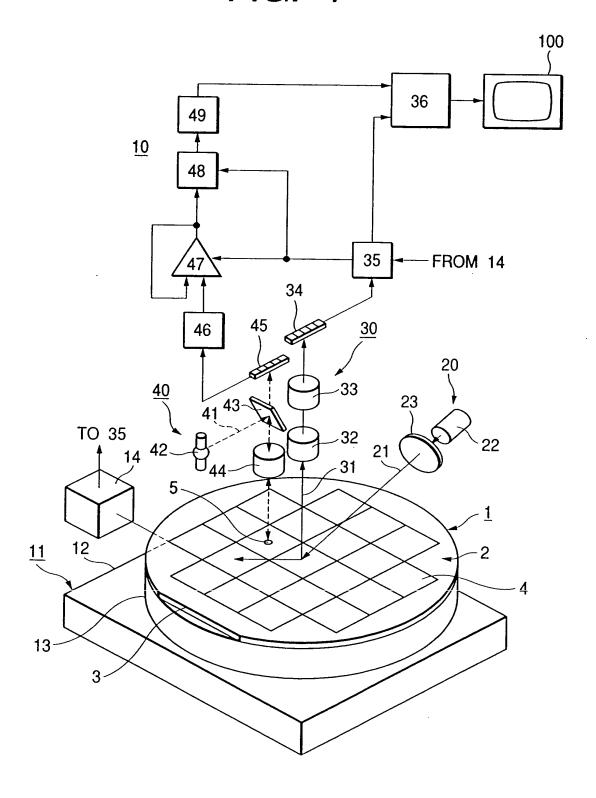
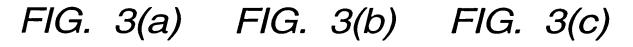


FIG. 2

DETECT OF FOREIGN MATTER AND DETERMINATION OF COORDINATE POSITION SEND COORDINATE POSITION TO COMPARING PORTION AND VERIFYING PORTION TAKE - IN OF IMAGE OF FOREIGN MATTER WHEN COORDINATE POSITION THEREOF COMES INTO ILLUMINATION POSITION TAKE - IN OF REFERENCE IMAGE WHEN SAME COORDINATE POSITION ON ADJACENT CHIP COMES INTO ILLUMINATION POSITION EXTRACT OF IMAGE OF FOREIGN MATTER BY COMPARISON OF BOTH IMAGES TAKEN - IN VERIFY DECISION OF DECISION DEVICE UPON PRESENCE OF IMAGE OF FOREIGN MATTER DETERMINE SIZES, SHAPE, COLOR, PROPERTY OF FOREIGN MATTER USING IMAGE THEREOF



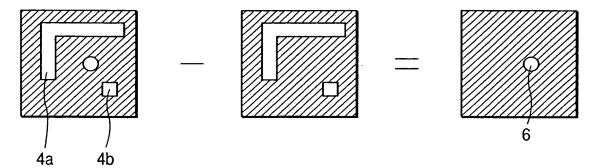


FIG. 3(d)

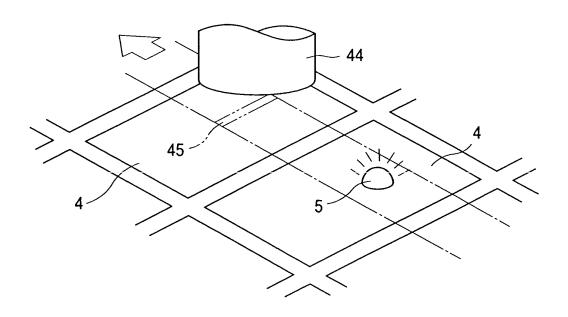


FIG. 4(a)

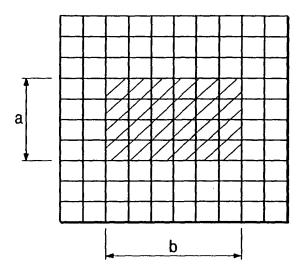


FIG. 4(b)

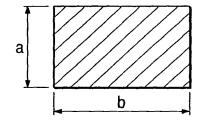


FIG. 4(c)

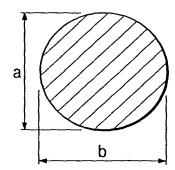


FIG. 4(d)

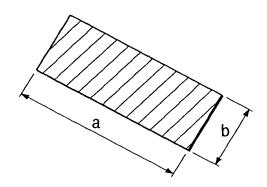


FIG. 5(a)

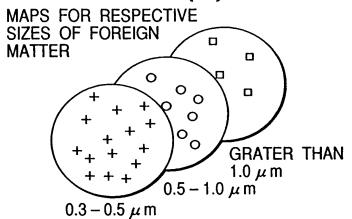


FIG. 5(b)

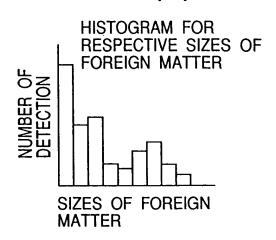


FIG. 5(c)

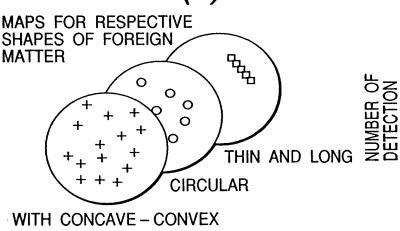


FIG. 5(d)

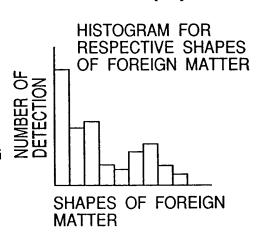


FIG. 5(e)

GRAPH OF RESULT OF INSPECTION IN TIME SEQUENCE

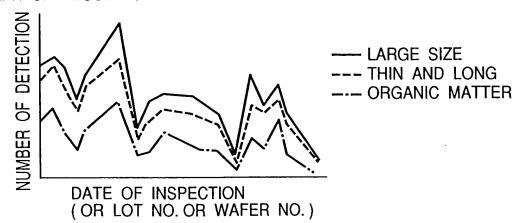


FIG. 6

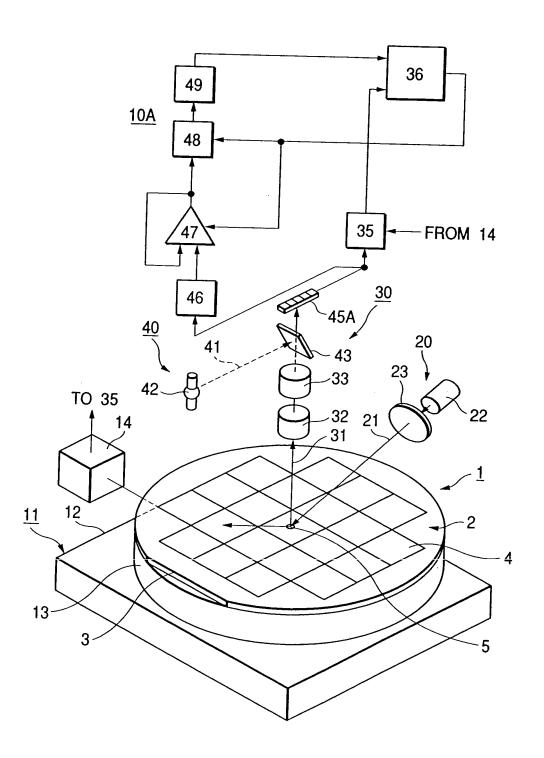


FIG. 7

DETECT OF FOREIGN MATTER AND DETERMINATION OF COORDINATE POSITION MEMORIZE COORDINATE POSITION OF FOREIGN MATTER GROUPING OR CLUSTERING OF FOREIGN MATTERS ON WAFER AND SAMPLING FOR PICK-UP OF IMAGE START OF EXTRACTION OF FOREIGN MATTER **IMAGE** TAKE - IN OF IMAGE OF FOREIGN MATTER WHEN COORDINATE POSITION THEREOF COMES INTO ILLUMINATION POSITION TAKE - IN OF REFERENCE IMAGE WHEN SAME COORDINATE POSITION ON ADJACENT CHIP COMES INTO ILLUMINATION POSITION

EXTRACT OF IMAGE OF FOREIGN MATTER BY COMPARISON OF BOTH IMAGES TAKEN - IN

VERIFY DECISION OF DECISION DEVICE UPON PRESENCE OF IMAGE OF FOREIGN MATTER

DETERMINE SIZES, SHAPE, COLOR, PROPERTY OF FOREIGN MATTER USING IMAGE THEREOF

FIG. 8(a)

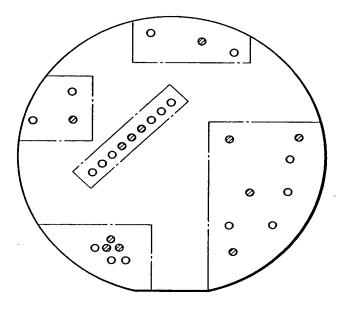
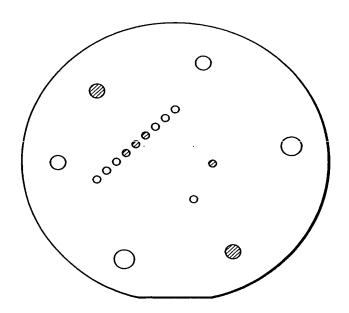


FIG. 8(b)



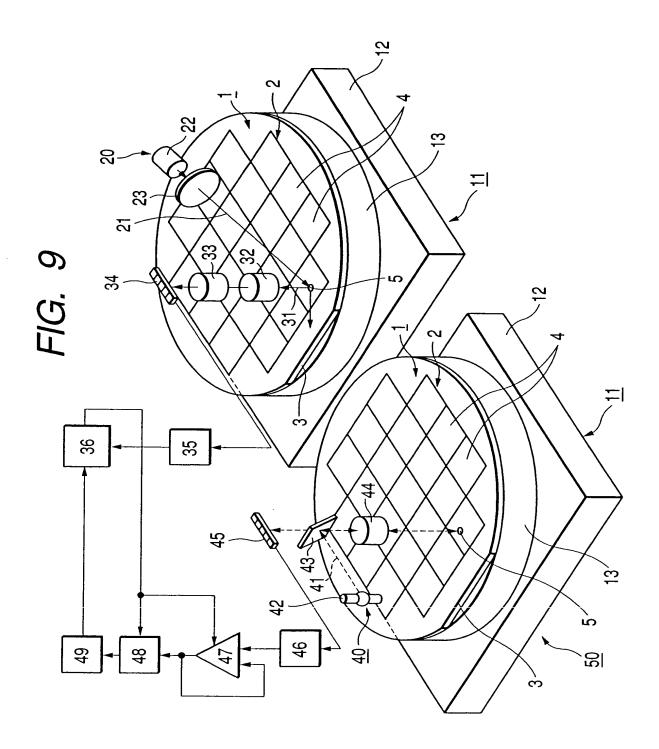


FIG. 10

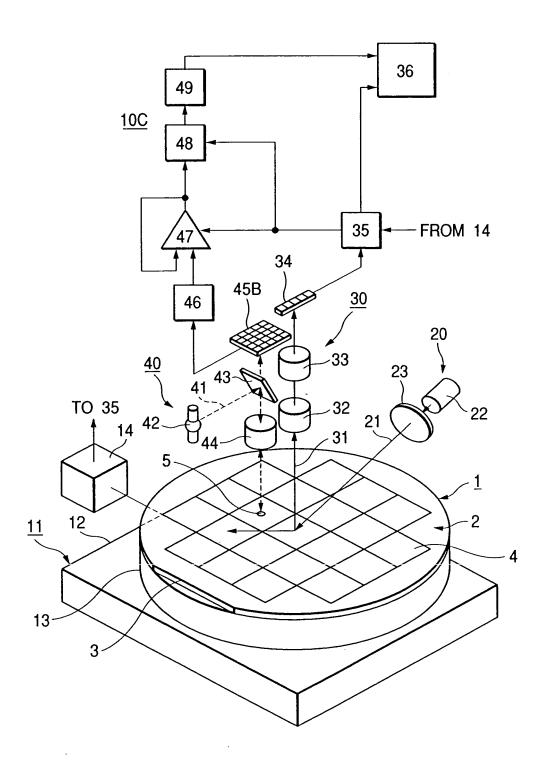


FIG. 11

DETECT OF FOREIGN MATTER AND DETERMINATION OF COORDINATE POSITION

SEND COORDINATE POSITION TO COMPARING PORTION AND VERIFYING PORTION

TAKE – IN OF IMAGE OF FOREIGN MATTER WHEN COORDINATE POSITION THEREOF COMES INTO ILLUMINATION POSITION

TAKE - IN OF REFERENCE IMAGE WHEN SAME COORDINATE POSITION ON ADJACENT CHIP COMES INTO ILLUMINATION POSITION

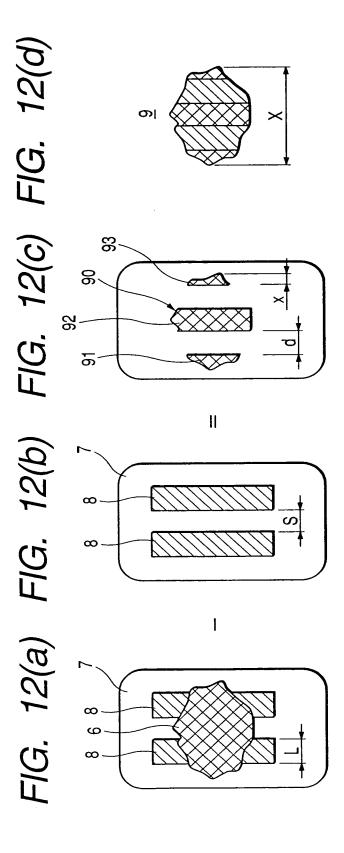
EXTRACT OF IMAGE OF FOREIGN MATTER BY SUBTRACTION BETWEEN BOTH IMAGES TAKEN – IN

VERIFY DECISION OF DECISION DEVICE UPON PRESENCE OF IMAGE OF FOREIGN MATTER

OBTAIN DIFFERENCE IMAGE BETWEEN OBJECT IMAGE AND REFERENCE IMAGE

ACKNOWLEDGE SINGLE FOREIGN MATTER FROM DISTANCE BETWEEN DIVIDED IMAGES AND BACKGROUND PATTERN IMAGE, AND DETERMINE KILLER DEFECT

DETERMINE SIZES, SHAPE, COLOR, PROPERTY OF FOREIGN MATTER USING IMAGE THEREOF



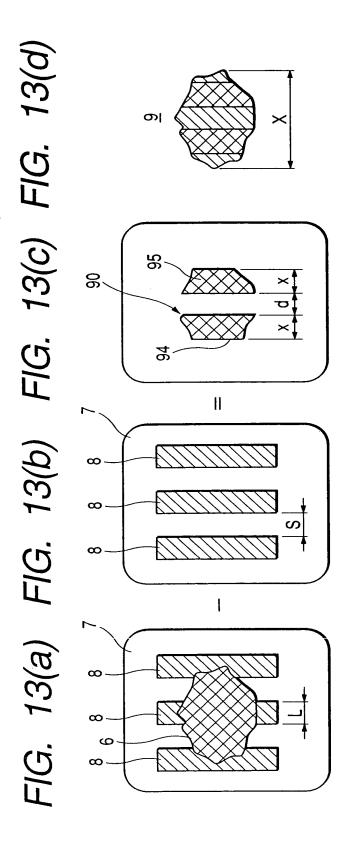
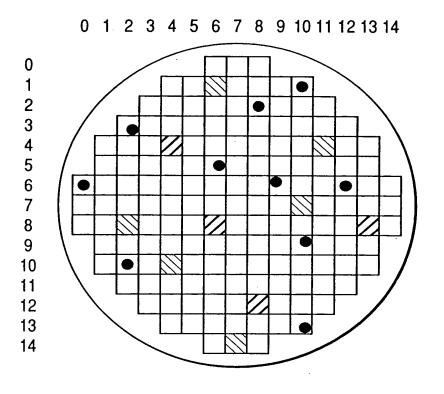


FIG. 14



- KILLER DEFECT CHIP (OMITTED ILLUSTRATION OF DETECTED FOREIGN MATTER)
- POSSIBLE DEFECT CHIP (OMITTED ILLUSTRATION OF DETECTED FOREIGN MATTER)
- GOOD CHIP

DETECTED FOREIGN MATTER

FIG. 15(a) FIG. 15(b) FIG. 15(c)

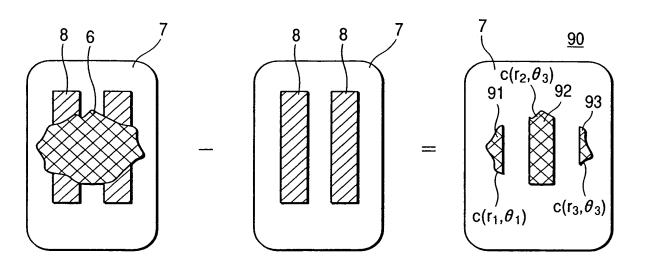


FIG. 15(d)

